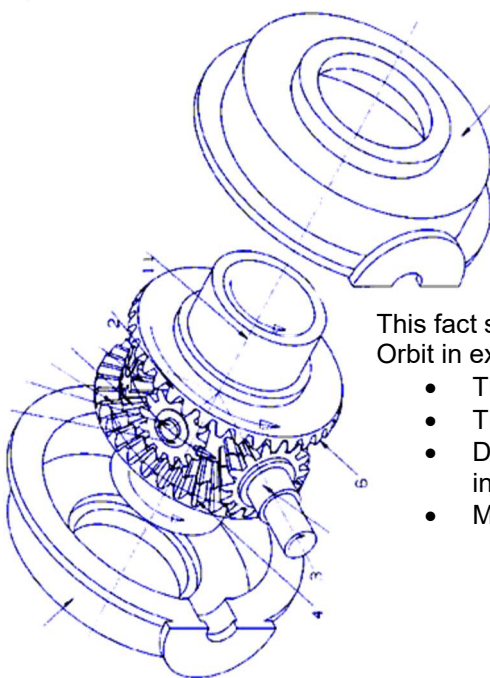


FullPat

**Worldwide collection of patents
containing bibliographic information, full text & legal status**



This fact sheet lists all of the available syntax and fields on Orbit in expert mode for:

- The Advanced Search wizard command line
- The Search History command line
- Drafting scripts in the Advanced Search wizard and in the Search History
- Modifying scripts in Saved Searches or Alerts

Contents

Title, Abstract, Key Info.....	2
Claims and Description.....	5
Concepts.....	6
Numbers and Dates.....	7
Classifications.....	12
Names.....	16
Citations.....	22
Legal Status.....	25
Count Fields.....	29
Other Indexes.....	30
Update Codes.....	31
Field Code Definitions.....	33
List of Technology Domains.....	37
List of Event Groups.....	38
List of US Reasons for Rejection.....	39

Title, Abstract, Key Content

Basic Index /BI and Super-Abstract /SA

Search by	Index	Search Hints	Examples
Basic Index (BI) + Super-Abstract (SA)	/BI/SA (default)	<p>If no other fields are specified, the search is conducted by default in the following fields:</p> <ul style="list-style-type: none"> • English title-all stages of publication (ETIH) • French title-all stages of publication (FTIH) • German title-all stages of publication (GTIH) • Title in another language-all stages of publication (OTIH) • English abstract (EAB) • French abstract (FAB) • German abstract (GAB) • Abstract in another language (OAB) • English Index Words-FR publications only (IW) • Drug name-French publications only (MED) • Object of the patent (OBJ) • Advantages and drawbacks of the invention over prior art (ADB) • Independent Claims (ICLM) <p>Search by :</p> <ul style="list-style-type: none"> - Single terms using operators - Phrases using implied adjacency <p>Truncation may be used. Left-hand truncation is available.</p>	SPEECH RECOGNIZER? AND FREELY PIVOT+
Basic Index (Titles and Abstracts)	/BI	/BI restricts the search to the ETIH, FTIH, GTIH, OTIH, EAB, FAB, GAB, OAB and MED fields.	(MEMORY MANAGEMENT AND SPEECH ???RECOGNIZER?) /BI
Super-Abstract Index (Key Content)	/SA	/SA restricts the search to 3 fields: OBJ, ADB and ICLM.	(PORTABLE AND MEASUR+ AND FLEXIB+ AND ACCELER+ AND FREELY PIVOT+) /SA

Details for fields in the BI and SA on next pages.

Basic Index (/BI) Details

Search by	Index	Search Hints	Examples
Title in English: Original, or official translation from the EPO or machine translation by Questel	/ETIH	Search with single terms using Boolean or proximity operators and/or phrases using implied adjacency. Truncation may be used and left- hand truncation is available. English language machine translations are replaced with the official English translations when available. /ETI restricts the search to English titles in the most recent publication stage.	(MEMORY AND SPEECH??) /ETIH
Original title in French Primarily available for the following patent authorities: WO, EP, FR, CA, BE, CH	/FTIH	Search in French with single terms using Boolean or proximity operators and/or phrases using implied adjacency. Truncation may be used and left-hand truncation is available /FTI restricts the search to French titles in the most recent publication stage.	(PALIER 1W ROULEMENT?) /FTIH
Original title in German Available for the following patent authorities: DE, EP, AT, CH, WO, DD	/GTIH	Search in German with single terms using Boolean or proximity operators and/or phrases using implied adjacency. Truncation may be used and left-hand truncation is available. /GTI restricts the search to German titles in the most recent publication stage.	WALZLAGER? /GTIH
Original title in other languages	/OTIH	OTIH and OTI contain original titles published in a language other than English, French, or German.	
/TI simultaneously searches the ETIH, FTIH, GTIH and OTIH fields. The title displayed in the TI field is from the most recent publication stage in the preferred language.			
Drug name with French SPC (Extension of a patent EP or FR)	/MED	Search with single terms using operators and/or phrases using implied adjacency. Not provided after September 2009	RIVAROXABAN /MED

Basic Index (/BI) Details (cont'd)

Search by	Index	Search Hints	Examples
English abstract: Original, or official translation from the EPO or machine translation by Questel	/EAB	If there is no official English abstract available, the /EAB field will contain the English machine translated abstract to be replaced by the official version when available. Search in English with single terms using operators and/or phrases using implied adjacency. Truncation may be used and left-hand truncation is available.	(TIME W INDEX) /EAB (PHENYL AND +VIRAL) /EAB
Original abstract in French Provided primarily for WO, EP, FR, CA, BE	/FAB	Search in French with single terms using operators and/or phrases using implied adjacency. Truncation may be used and left-hand truncation is available.	(COLLECTEUR SOLAIRE PLAT AND CHAMBRE? AND (SOUS W VIDE)) /FAB
Original abstract in German Provided for DE from 1982, EP from 1978 and WO from 1995	/GAB	Search in German with single terms using operators and/or phrases using implied adjacency. Truncation may be used and left-hand truncation is available.	BELEUCHTUNGSEINRICHTUNG /GAB
Original abstract in other languages Mainly available from 1984	/OAB	Abstracts published in other languages such as: - Russian (SU, RU) - Japanese (JP) - Chinese (CN, TW) - Korean (KR) - Italian (IT) - Portuguese (BR, PT) - Spanish (ES, MX, AR, CR, PA, PE, NI, SV, UY, GT, CO, EC, CU, CL, DO, WO) - Turkish (TR) - Hungarian (HU)	
/AB simultaneously searches the EAB, FAB, GAB and OAB fields. The abstract displayed in AB is one that meets the preferred language.			

Abstracts Super-Index

Search by	Index	Search Hints	Examples
All abstracts and index words	/ABS	Using the Super-Index /ABS searches all abstract fields simultaneously: EAB, FAB, GAB and OAB.	(+PHENYL AND VIRAL+) /ABS

Key Content Super-Index (/SA) Details

Extracted from the fulltext of the Original English language publications: AU, CA, EP, GB, IN, US, PCT and English machine translated publications: CN, DE, FR, IL, JP, KR

Search by	Index	Search Hints	Examples
Object of invention	/OBJ	Search in English using single terms with operators and phrases using implied adjacency. Use truncation.	(PORTABLE AND MEASUR+ AND FLEXIB+ AND CLUB HEAD) /OBJ
Advantages of the invention & Drawbacks over prior art	/ADB		(ELECTRONIC? AND ACCELER+) /ADB
Independent Claims: Including main or first Claim	/ICLM		(FREELY PIVOT+) /ICLM

Claims and Description*

Search by	Index	Search Hints	Examples
Claims in: - English - French - German - Other languages	/ECLM /FCLM /GCLM /OCLM	Search by: - Simple words using operators - Phrases using implied adjacency Use truncation. Left-hand truncation is available.	(PORTABLE AND MEASUR+ ET FLEXIB+ AND CLUB HEAD) /ECLM
Description in: - English - Other languages	/DESC /ODES		(ELECTRONIC? AND ACCELER+) /DESC
Examples included in the description of US publications from 1976	/DESX		((OVABULMIN OR OVA) AND ENCAPSULAT+) /DESX
All claims	/CLMS	/CLMS simultaneously searches the ECLM, FCLM, GCLM and OCLM fields. The claims displayed in CLMS are claims that meet the preferred language	((COLLAPS+ OR PLIANT OR PLIABLE) AND (CLAVIER OR KEYBOARD)) /CLMS
All Claims and Descriptions	/TX	/TX simultaneously searches the ECLM, FCLM, GCLM, OCLM, ODES, DESC and DESX fields.	(FREELY PIVOT+) /TX
<p>* For full text coverage details (original language and English translation): https://static.orbit.com/imagination/orbit_welcome/prd/coverage/coverage.htm </p>			

Concepts

Concepts are extracted from the full text of the patent publications using linguistic technology. They reflect the semantic content of the patent and are ranked by decreasing score.

The following publications are used to extract the concepts and also reflect the patenting authorities for in which the field is searched:

Original English language publications: AU, CA, EP, GB, IN, US, PCT

English machine translated publications: CN, DE, FR, IL, JP, KR

Search by	Index	Search Hints	Examples
Concepts	/KEYW	Search by single terms using operators, or by phrases using implied adjacency. Use truncation. Left-hand truncation is available.	(DRUM GRANULATOR) /KEYW
In Kwic display following a concept search, the figures that appear in parentheses after each concept represent the score of the concept and its number of occurrences. They are not searchable			

Numbers and Dates

Publication Data

Search by	Index	Search Hints	Examples
Publication data:: - Number - Country - Kind code - Kind code and office - Date	/PN	All the patent publication stages are searched with /PN. • Search using the patent/publication number in the following formats: - If patent authority uses a continuous series: CCNNNNNNN If the number is <7 digits, infill with hyphen(s) after the country code to achieve the necessary number of characters. - If the patent authority restarts its number series each year: Before 2000: CCYYNNNNN (if number is <5 digit, fill with zeros after the series year CCYY) After 2000: CCYYYYNNNNN CCYYYYNNNNNN • Search for publications by ISO 2-letter country code • Search by kind code. Truncation ? or # may be used. Search in the format CCKK. CC = country code KK = status code • Search by publication date without numeric operators: YYYY-MM-DD YYYY-MM YYYY • To combine publication country and date, use the S operator.	EP-982976/PN NL--94451/PN WO9916958/PN WO8909788/PN WO200016958/PN US20010000001/PN KR20190131157/PN US/PN B2/PN B#/PN EPA? /IKD EPB# /IKD 1995-06-25/PN 1995-06/PN 1995/PN (EP S 2005) /PN
Questel standardized publication number	/XPN	The normalized publication number is unique. Its format is defined by Questel	EP-982976/XPN
Original PCT publication number	/PPN	Search with: • Questel standardized format: Before 2000: CCYYNNNNN After 2000: CCYYYYNNNNN • Publication date without numeric operators • Presence of the field	WO9838673 /PPN WO200353458 /PPN 1998-11 /PPN PPN=YES

Publication Data (cont'd)

Search by	Index	Search Hints	Examples
Publication dates (except OPD): - All publication dates - First publication date - Last publication date	/PD /PDF /PDL	Search in the format: YYYY-MM-DD YYYY-MM YYYY Use numeric operators: =, <, >, <=, >=	PD=2000-02-16 PDF<=1997-06 PDL>1995 PD=1997-04-01:1997-05-15
First application publication date	/PDA		PDA=2008-10-02 PDA<=1999-10 PDA>2007 PDA=2007-06:2008-09
Granted patent date	/PDG	Presence of the field can also be used especially with the PDG field.	PDG=1998-06-02 PDG=YES
Other publication dates: - Effective date - Date of previous issue - Date of national stage U.S.C. 371 - Examination requested - Entry into national stage date - Date of coming into force	/OPD	Nature of the OPD is displayed within parentheses but not searchable	OPD=2006-01-12 OPD<=2006-01 OPD>2006
Publication stage	/STG	Search by term for the type of publication. Note: This field is not standardized. It is recommended to use the Kind Code (see KK/PN or CCKK/PN previous page).	(PATENT OR GRANTED) /STG
Publication language	/LA	Search using the English name of the language or using the ISO three letter language codes	ENGLISH /LA ENG /LA

Application Data

Search by	Index	Search Hints	Examples
Filing Data: - Number - Country - Date	/AP	Search using: <ul style="list-style-type: none"> The application number in the format YYYYCC-NNNNNNN YYYY = 4-digit application year CC = ISO country code NNNNNNN= 7 digit application number (fill in with zero(s) if number contains less than 7 digits) US application numbers are searched using the 2-digit series code between US and the serial number. Format: USSCNNNNNN US = country code SC = the 2-digit US series code (infill with zeros if < series code 10) * <ul style="list-style-type: none"> The application country using the two-letter ISO country code Receiving office code in a WO application number is searched using WO followed by the 2-letter ISO country code <ul style="list-style-type: none"> The application date in the format: YYYYMMDD YYYYMM YYYY Do not use numeric operators. 	1999EP-0202618 /AP 1989WO-US01469 /AP US13974634/AP US08352062 /AP EP /AP WOJP/AP 1999-08-12 /AP 1999-08 /AP 1999 /AP
Questel standardized application number	/XAP	The normalized application number is unique. Its format is defined by Questel.	1999EP-0202618 /XAP
Application (Filing) Date	/APD	Search in the format: YYYY-MM-DD YYYY-MM YYYY Use numeric operators: =, <, >, <=, >=	APD=1999-08-12 APD=1999-06:1999-10 APD>=1992
Application data from parent document - Parent WO - Parent EP	/PAP /EPAP	Search using: - Presence of the field - The number in the format: YYYYWO-CCNNNNN or YYYYEP-NNNNNNN - The application date with the PAPD or EPAD subfields and numeric operators	PAP=YES EPAP=YES 2002WO-CU00011 /PAP 2010EP-0745681 /EPAP PAPD/PAP=2002-11 EPAD/EPAP>2012
Filing Language	/APL	Search using the English name of the language or using the ISO three letter language codes	ENGLISH /LA ENG /LA
* For a list of US Series codes: www.uspto.gov/web/offices/ac/ido/oeip/taf/filingyr.htm			

Application Data (cont'd)

Search by	Index	Search Hints	Examples
Filing Details Provides information such as whether one patent is based upon another (continuation of, CIP, division of).	/FD	Search using: - Presence of the field - Standardized Questel format YYYYCC-NNNNNNN - Date using the FDD subfield and numeric operators	FD=YES 1995US-60000189 /FD FDD/FD=2010
Designated states for European Patents (EP) and PCT applications (WO)	/DS	Search by ISO country code using the 2-letter format CC. The EP designated states are from the last EP publication stage.	AT /DS (FR OR GB) /DS
Family Accession Number in FamPat	/FAN	Sequential number assigned to a FamPat family	66142304 /FAN
Extended Family Accession Number	/EFAN	Sequential number assigned to an extended family	1000726 /EFAN
Application ID	/APID	Sequential number assigned to the document in the FullPat record and which is kept by each member in the FamPat family APID can change following an application number modification.	107523059 /APID
EPO Family ID (EPO coverage)	/FID	Sequential number assigned to an EPO simple patent family.	75239191 /FID

Priority Data

Search by	Index	Search Hints	Examples
Priority Data: - Number - Country - Date	/PR	Search using: • The priority number in the format: YYYYCC-NNNNNNN YYYY = 4-digit application year CC = ISO country code NNNNNNN = 7 digit application number (fill in with zero(s) if number contains less than 7 digits) US Priority Numbers are searched using the 2-digit series code between US and the serial number Format: USSCNNNNNN US = country code SC = the 2-digit US series code (fill in with zeros if < series code 10)* • The priority country using the two-letter ISO country code • Receiving office code in a WO application number is searched using WO followed by the 2-letter ISO country code • The priority date in the format: YYYYMMDD YYYYMM YYYY Do not use numeric operators.	1986NL-0003303 /PR 2001WO-US06520 /PR US11962576/PR US08352062 /PR US /PR WODE/PR 1998-08-12 /PR 1998-08 /PR 1998 /PR
Questel standardized priority number	/XPR	The normalized priority number is unique. Its format is defined by Questel.	2000US-09747259/XPR
Priority Date: - All priority dates - Earliest priority date - Latest priority date	/PRD /PRDF /PRDL	Search in the format: YYYY-MM-DD YYYY-MM YYYY Use numeric operators: =, <, >, <=, >=	PRD=1998-08-12 PRD=1998-04:1998-08 PRDF>=1997 PRDL<=2014-10
Earliest priority country	/EPRC	Search using the two-letter ISO country code.	US /EPRC (US OR JP)/EPRC
Number of priorities	/NPR	Use numeric operators: =, >, <, >=, <=.	NPR=3 NPR>1
* For a list of US Series codes: www.uspto.gov/web/offices/ac/ido/oeip/taf/filingyr.htm			

Classifications

Technology Domains

Search by	Index	Search Hints	Examples
Technology Domain 35 areas listed page 37	/TECD	Questel indexing based on class titles or subclasses of the IPCs. Search with single terms using operators and/or phrases using implied adjacency. Truncation may be used.	OPTICS /TECD (MACHINE TOOL?) /TECD

International Patent Classification

Search by	Index	Search Hints	Examples
International Patent Classification Data	/IPC	<p>The /IPC index simultaneous searches the following fields:</p> <ul style="list-style-type: none"> • <u>ICH</u>: Codes as they have been assigned by national offices at each stage of publication /ICH can restrict the search to historical IPC codes. • <u>IC</u>: Updated Codes /IC allows you to restrict the search to updated IPC codes. <p>Search with one of the following formats:</p> <ul style="list-style-type: none"> - full index: ANNA-NNN/NN - group*: ANNA-NNN - subclass*: ANNA - class: ANN #: use the # symbol. <p><i>* These two formats are searchable without truncation.</i></p>	<p>G10L-015/26 /IPC G10L-015 /IPC G10L /IPC G10# /IPC</p>
-Main classification code	/ICM	The index /ICM allows you to restrict the search to the main code.	H01M-008 /ICM

Cooperative Patent Classification

Search by	Index	Search Hints	Examples
<p>CPC Classification Data (Cooperative Patent Classification)</p> <p>CPC is used in place of ECLA and ICO since 1 January 2013.</p>	/CPC	<p>The /CPC index simultaneous searches the following fields:</p> <ul style="list-style-type: none"> • CPC: Codes as they were granted by the EPO and the USPTO at each stage of publication /CPC can restrict the search to historical CPC codes. • CPC: Updated Codes <p>Search by:</p> <ul style="list-style-type: none"> - Full code (conversion of ECLA and mirrored ICO codes) ANNA-NNN/NN ANNA-NNN/NN/NNN ANNA-NNN/NNN/NN (2-3 digits after the first slash, 1-3 digits after second the slash - Entering the second slash is optional). - Full code (conversion of orthogonal ICO codes) ANNA-2NNN/NNNNN (2-5 digits after the slash) - Group*: ANNA-NNN or ANNA-2NNN - Subclass*: ANNA - Class: ANN#; use the # mask. <p><i>* These two formats are searchable without truncation.</i></p>	<p>G06K-019/02 /CPC G06K-019/02/7 /CPC G06K-019/06/065 /CPC G06K-019/077/43 /CPC</p> <p>G06K-019/06065 /CPC</p> <p>A01D-2017/108 /CPC H01L-2021/60292 /CPC</p> <p>G06K-019 /CPC A01D-2017 /CPC G10K /CPC G10# /CPC</p>
/ Main classification code	/CPCM	The index /CPCM allows you to restrict the search to the main code.	A01D-2017/108 /CPCM
<p>-Combination group of CPC</p> <p>(an ordered list of linked CPC symbols created by patent examiners)</p>	/CPCG	<p>The index /CPCG allows you to search linked CPC codes in a combination group.</p> <p>Specify the search using the rank for each code</p>	<p>(C07C-067/02 L C07C-069/54)/CPCG</p> <p>((C08L-077/00 W RK1) L (C08L-067/00 W RK2))/CPCG</p>
<p>Concordance between the old ECLA and ICO codes and new CPC codes is available on the EPO website: www.cooperativepatentclassification.org/cpcConcordances.html </p>			

Former European Classifications

Search by	Index	Search Hints	Examples
<p>ECLA and In Computer Only Classifications Data</p> <p>Used by EPO examiners until 2012 - Replaced by CPC</p>	/EC	<p>Search by:</p> <ul style="list-style-type: none"> - Full index: <ul style="list-style-type: none"> ANNA-NNN/NNN ANNA-NNN/NNA ANNA-NNN/NNAN ANNA-NNN/NNANA ANNA-NNN/NNANAN - Group*: ANNA-NNN - Subclass*: ANNA - Class: ANN#; use the # mask. <p><i>* These two formats are searchable without truncation.</i></p> <p>ICO is derived from ECLA and where the letters A, B, C, D, E, F, G and H are replaced by the letters K, L, M, N, P, R, S and T.</p> <p>Was used for:</p> <ul style="list-style-type: none"> - Describe the characteristics for which there is also an ECLA code and classifies additional information (mirrored codes) - Describe the characteristics for which there is no ECLA code (orthogonal codes) - Classify information according to different criteria compared to ECLA (additional subdivisions ECLA) <p>ICO - two classes were created to cover nanotechnology (Y01) and sustainable energy technologies (Y02).</p>	<p>C21D-001/773 /EC</p> <p>C21D-006/00K /EC</p> <p>B25G-001/06S1 /EC</p> <p>G10L-015/06A3S /EC</p> <p>C12Q-001/68D2E1 /EC</p> <p>G10L-015 /EC</p> <p>G10L /EC</p> <p>G10# /EC</p> <p>S10L-015/18C1 /EC</p> <p>M08L-009/06 /EC</p> <p>M08L-009 /EC</p> <p>M08L /EC</p> <p>M08# /EC</p>

United States Classification

Search by	Index	Search Hints	Examples
US Classification Data: (for US documents only) - Historical codes - Updated codes	/PCLH /PCL	The US classification code (9 or 12 characters) is formatted as: MMMSSDDDDAAA MMM = 3-digit class SSS = 3 digit subclass or DIG for "Digest" DDD = 3 digits AAA = 1-3 optional alphanumeric characters Search by : - Class - Subclass or Digest including mention DIG - Full code For a comprehensive search, use both fields simultaneously.	379 /PCL 379093 /PCL 210DIG017 /PCL 379093150 /PCL 379093150 /PCL/PCLH
- Main classification code	/PCLM	The /PCLM index allows you to restrict the search to the main classification.	343754 /PCLM

Japanese Classification

Search by	Index	Search Hints	Examples
FI and F-terms (for JP documents only) - FI (File Index) Contains no additional zeros or dashes (unlike Questel format for IPCs)	/FI	Classification derived from the 6th edition of the IPC and used by JPO examiners for Japanese documents. <u>The FI may be made of:</u> - An IPC code in the format : ANNA[N]N/NN[N] - An IPC code followed by a symbol (1 letter) in the format: ANNA[N]N/NN[N] A - An IPC code followed by a subdivision (3 digits) in the format: ANNA[N]N/NN[N]NNN - An IPC code followed by a subdivision and a file symbol in the format: ANNA[N]N/NN[N]NNNA - An IPC code with a "facet" (3 letters)	A01B1/16 /FI G10L9/20A /FI G11B11/105506 /FI G11B11/105506A /FI G11B11/08ZNM /FI
- F-term (File Forming Term)	/FTM	All technical areas covered by FIs are defined themes and some of these themes are divided into F-terms. <u>Search by:</u> - Theme in format NANNNNANNN - Theme and point of view in format NANNNA+ - Full F-term in format NANNNAANN or NANNNAANN.N	4C206 /FTM 4C206CB+ /FTM 4C206CB23 /FTM 4J002AC03.3 /FTM

Names

Inventor

Search by	Index	Search Hints	Examples
<p>Name of the inventor:</p> <ul style="list-style-type: none"> - At each stage of publication - At the most recent publication stage - In non-Latin original language 	<p>/INH</p> <p>/IN</p> <p>/OIN</p>	<p>The /INH index searches the name of the inventor for all stages of publication.</p> <p>The index /IN restricts the search to the inventor at the most recent publication stage.</p> <p>For CN, JP, KR, RU publications, a human validated translation is provided for major inventors. Otherwise an English machine translation is provided for CN, JP, KR, RU, TW and TH , automatically replaced by the official data when it becomes available.</p> <p>Search by single terms (operators) or phrases (implied adjacency), using truncation Use the D or S operator to combine full name (first and surname in full, because the two entries co-exist). For a comprehensive search, use both fields simultaneously.</p> <p>Search by the name of the inventor in non-Latin original language for CN, JP, KR, TW, RU/SU publications and for PCT applications published in Russian, Korean, Japanese and Chinese.</p>	<p>(KAO D (YO W HONG)) /IN</p> <p>(KAO YO HONG) /IN</p> <p>(PUYPLAT S (O OR OLIVIER)) /IN</p> <p>SMITH /IN/INH</p>
<p>Inventor Address:</p> <ul style="list-style-type: none"> - Country - State - Postcode 	/INAD	<p>Search by:</p> <ul style="list-style-type: none"> - ISO 2-letter country code using the COUNTRY subfield. - ISO 2-letter US State code* using the STATE subfield. - Prefecture, province name To get complete results, any STATE search should be performed in the subfield and in /INAD directly - Full or truncated post code using the POSTCODE subfield To combine several subfields, use the P operator 	<p>COUNTRY/INAD=US</p> <p>STATE/INAD=ME</p> <p>STATE/INAD=NAGANO STATE/INAD=HENAN OR HENAN/INAD</p> <p>(POSTCODE/INAD=69+ OR 69####/INAD) P COUNTRY/INAD=FR</p>
<p>* For a list of US State codes: about.usps.com/who-we-are/postal-history/state-abbreviations.htm</p>			

Inventor (cont'd)

Search by	Index	Search Hints	Examples
- City	/INAD	<p>Search by:</p> <p>- Name of the city</p> <p>Postcode can be found in front of the city name in CITY subfield (mainly for European cities). Search European cities in CITY subfield using left hand truncation</p> <p>To get complete results, any CITY search should be performed in the subfield and in /INAD directly</p>	<p>(CITY/INAD=+PARIS OR PARIS/INAD) P COUNTRY/INAD=FR</p> <p>CITY/INAD=LOS?ANGELES OR (LOS W ANGELES)/INAD</p>

Applicant or Assignee

Search by	Index	Search Hints	Examples
<p>Name of the applicant or assignee:</p> <p>- At each stage of publication</p> <p>- At the most recent publication stage</p>	<p>/PAH</p> <p>/PA</p>	<p>The /PAH index searches the name of the applicant or assignee for all stages of the publication in the EPO format.</p> <p>The PA field contains the standardized assignee name (see NPA). If this is not available, contains the name at the most recent publication stage.</p> <p>For CN, JP, KR, RU, TH and TW publications, a human validated translation is provided for major applicants. Otherwise an English machine translation is provided, automatically replaced by the official data when it becomes available.</p> <p>Search by single terms (operators) or phrases (implied adjacency), using truncation For a comprehensive search, use both fields simultaneously.</p> <p><u>Note:</u> The PAN field (corresponding to the PA field in keywords) is useful to search exact term.</p>	<p>(TEXAS W INSTRUMENT?) /PA</p> <p>(KIMBERLY CLARK) /PA/PAH</p> <p>FAURECIA/PAN</p>
- In non-Latin original language	/OPA	Search by the name of the applicant in non-Latin original language for CN, JP, KR, TW, RU/SU publications and for PCT applications published in Russian, Korean, Japanese and Chinese.	

Applicant or Assignee (cont'd)

Search by	Index	Search Hints	Examples
Standardized patent assignee name of each member	/NPA	<p>This field provides the name of company standardized by Questel. This standardization includes corrections of typographical errors, the removal of non-meaningful parts of the name such as legal forms (INC, SA, GmbH, LTD, etc.) and removing spaces and periods in acronyms. The field will supply, if possible, the latest name of the company. Names are deduped when they are exactly identical for different members.</p> <p>Search by single terms using search operators and truncation or full name using implied adjacency.</p> <p><u>Note:</u> The NPAN field (corresponding to the NPA field in keywords) is useful to search exact term.</p>	<p>PANASONIC /NPA</p> <p>FAURECIA /NPAN</p>
<p>Reassignments:</p> <p>(Sources: Inpadoc data and CA, CN, EP, US patent offices)</p> <p>- Reassignment type</p>	/REAS	<p>Search by:</p> <ul style="list-style-type: none"> - Presence of field - Single words (operators) or phrases (implied adjacency) <p>Search in the TTYP subfield:</p> <ul style="list-style-type: none"> - "Reassignment from inventor to company" using the IN code - "First applicant/assignee" (CO) - "Reassignment from company to individual" (IO) - "Company name change" (CNC) - "Reassignment from one company to another distinct company" (C2C) 	<p>REAS=YES</p> <p>PANASONIC /REAS</p> <p>PANASONIC /REAS AND HITACHI /PA</p> <p>TTYP/REAS=IN</p> <p>TTYP/REAS=CO</p> <p>TTYP/REAS=IO</p> <p>TTYP/REAS=CNC</p> <p>TTYP/REAS=C2C</p> <p>CARRIER/REAS S</p> <p>TTYP/REAS=C2C</p>

Applicant or Assignee (cont'd)

Search by	Index	Search Hints	Examples
Assignee Address: - Country - State - City - Post code	/PAAD	Search by: - ISO 2-letter country code using the COUNTRY subfield - ISO 2-letter US state code* using the STATE subfield - Prefecture, province name For names containing an hyphen, use limited truncation ?. - City name using the CITY subfield and the PAAD field For names containing an hyphen, use limited truncation ?. To get complete results, any CITY or STATE search should be performed in the subfield and in /PAAD directly - Full or truncated post code using the POSTCODE subfield and the PAAD field To combine several subfields, use the P operator.	COUNTRY/PAAD=JP STATE/PAAD=CO STATE/PAAD=NAGANO STATE/PAAD=NEW?SOUTH ?WALES OR (NEW W SOUTH W WALES)/PAAD CITY/PAAD=LYON OR LYON/PAAD (CITY/PAAD=CLERMONT?F ERRAND) OR (CLERMONT W FERRAND)/PAAD ((POSTCODE/PAAD=68+) OR (68###)/PAAD) P COUNTRY/PAAD=FR
* For a list of US State codes: about.usps.com/who-we-are/postal-history/state-abbreviations.htm			

Names Super-Index

Search by	Index	Search Hints	Examples
Inventor + Assignee	/NA	This field allows for simultaneous searching of the Inventor and Assignee fields: IN, PA.	GUTMANN /NA

Representative

Search by	Index	Search Hints	Examples
Representative name	/RP /RPH /ORP	Search by single terms (operators) or phrases (implied adjacency), using truncation. For names of people, use the D or S operators to combine first name and surname. The /ORP index allows to search by the name of the representative in non Latin original language for JP, CN, KR, TH and WO publications.	GUIU /RP GUIU /RPH (ERNEST S GUTMANN) /RP (ERNEST S GUTMANN) /RPH 阿部 琢磨/ORP
Representative country	/RPAD	.Search by 2-letter country code using the COUNTRY subfield.	COUNTRY/RPAD=DE

Business Name Entity

Search by	Index	Search Hints	Examples
Parent Company Name	/BPA	<p>Search by Parent company name using single terms using search operators and truncation or full name using implied adjacency. This field allows for searching by a Parent company associated to Assignees owned by this entity</p> <p><u>Note:</u> The BPAN field (corresponding to the BPA field in keywords) is useful for searching exact term.</p>	<p>(SCHNEIDER D ELECTRIC) /BPA</p> <p>(SCHNEIDER D ELECTRIC) /BPAN</p>
-Annual Revenue of the Top Entity (millions USD \$)	/BNT	- Search using the REV subfield and numeric operators	REV/BNT=40:50

Other Names

Search by	Index	Search Hints	Examples
<p>License interest name: (US et CN only)</p> <p>-License year</p> <p>-License type (US only)</p>	/LIC	<p>Search by :</p> <ul style="list-style-type: none"> - Presence of field - Licensee name using single words (operators) or phrases (implied adjacency) - License year using keywords FROM for the beginning of the license and TO for the effective end of the license - License type using the LT subfield and keywords CONFIRMATORY for government licenses and LICENSE for the other licenses (Available for US documents only) 	<p>LIC=YES</p> <p>APPLE /LIC</p> <p>(FROM 2007) /LIC</p> <p>(TO 2016) /LIC</p> <p>LT/LIC=CONFIRMATORY</p> <p>LT/LIC=LICENSE</p>
<p>Security interest name</p> <p>Available for US documents only (USPTO source)</p>	/SEC	<p>Search by:</p> <ul style="list-style-type: none"> - Presence of field - Name of the financial organization using single words (operators) or phrases (implied adjacency) - Pledge year using keywords FROM for the beginning of the pledge and TO for the effective end of the pledge 	<p>SEC=YES</p> <p>(BARCLAYS BANK) /SEC</p> <p>(FROM 2012) /SEC</p> <p>(TO 2014) /SEC</p>

Citations

Citations (patent and non patent literature references) are available for the following publications:

AP – from 1985	DK – from 1956	IT – from 2008	PH – from 2019
AT – from 1983	EA – from 1998	JP – from 1965	PL – from 2019
AU – from 1987	EE – from 2019	KR – from 2006	PT – from 2012
BE – from 1988	EP – from 1978	LT – from 1994	RU – from 2012
BG – 2004-2011	ES – from 1993	LU – from 1998	SG – from 2001
CH – from 1963	FI – from 1990	LV – from 2017	TR – from 1987
CN – from 1997	FR – from 1969	MD – from 1998	TW – from 2013
CY – from 2004	GB – from 1979	MY – 2003-2009	US – from 1947
CZ – from 2006	GR – from 1988	NL – from 1965	WO – from 1978
DE – from 1943	HR – from 1994	NO – from 2004	

Patents cited in search reports are displayed in the CT field under the title « Search Report » or « Examiner citations » for all the countries listed above.

- For AT, BE, CH, DE, DK, EP, FR, GR, KR, LT, LU, NL, TR, US and WO publications, this field also contains Applicant citations.
- For EP publications, this field also contains Opposition citations and Observer Citations (art. 115).
- For JP publications, citations are listed in 4 categories: Opposition citations (reason for opposition), Opposition citations (reason for decision), Examiner citations (reason for refusal) and Citations in registration report.

Search is detailed on next page: /CTN index for searching for cited patents and /CTGN index for searching for citing patents.

Cited non patent literature is available for all the countries listed above.

References to cited non patent literature are displayed in the REF field under the title « Search report references » or « Examiner references ».

- For US, EP, WO, FR, DE, NL, BE, IT, GR, CH, GB, TR, LT, LU and DK publications, the REF field also contains applicant literature references.
- For EP publications, the REF field also contains Opposition references and Observer references (art. 115).

Search by	Index	Search Hints	Examples
Non patent literature Citations	/REF	Search using single words (operators) or phrases (implied adjacency), using truncation on: - Title - Authors - Source - XP number assigned by the EPO examiners - Presence of the field	(RECOGNITION W SYSTEM?) /REF DESHMUKH /REF (SIGNAL 1W MAGAZINE) /REF XP002058560 /REF REF=YES
Standards citing a patent (Standards issued mainly by ETSI*)	/STDN	Search by : - Standard number using the NAME subfield - Presence of the field	NAME/STDN=ETSI-TS-36-331 STDN=YES
* Sources for STDN: ETSI (European Telecommunications Standards Institute), ITU (International Telecommunication Union), IEC (International Electrotechnical Commission), IETF (Internet Engineering Task Force), OMA (Open Mobile Alliance), IEEE (International Electrotechnical Commission), ISO (International Organization for Standardization), ANSI (American National Standards Institute), ATIS (Alliance for Telecommunications Industry Solutions), TIA (Telecommunications Industry Association), BBF (BroadBand Forum), CEN (European Committee for Standardization), CENELEC (European Committee for Electrotechnical Standardization)			

Citations (cont'd)

Search by	Index	Search Hints	Examples
Standardized cited patent	/CTN	Search by presence of the CTN field to retrieve documents with cited patents, by presence of the CTGN field to retrieve documents with citing patents.	CTN=YES
Standardized citing patents	/CTGN		CTGN=YES
- Publication number		Search by standardized patent number in the format CCNNNNNNNN (same as the PN field). Fill with hyphens if needed.	EP-248377 /CTN USD308968 /CTGN
- Citation author		Search by keywords below using the WHO subfield: - Applicant - Examiner - Third_Party - Unknown	WHO/CTN=APPLICANT WHO/CTGN=EXAMINER
- Self citation		Search by Keyword Y (for yes) or N (for no) using the SELF subfield.	SELF/CTN=Y SELF/CTGN=N
- EPO Examiner citation categories		Search by relevancy codes above using the CAT subfield. Used by the EPO in their search reports, Relevancy category codes are found in EP, FR and PCT search reports. . I Particularly relevant when taken alone affecting the inventive action X Particularly relevant if taken alone and affecting novelty Y Particularly relevant if combined with another document in the same family A Technology background O Unwritten disclosure P Intermediate document T Theory or principle underlying the invention E Earlier patent document, but published on, or after, the filing date D Document cited in the application L Document cited for other reasons	CAT/CTN=I OR CAT/CTN=X
Questel standardized cited patent number	/XCT	The normalized cited patent number is unique. Its format is defined by Questel	EP-248377 /XCT

Citations (cont'd)

Search by	Index	Search Hints	Examples
- USPTO Examiner citation categories	/CTN	<p>Search by relevancy codes above using the CAT subfield.</p> <p>Extracted from the US file wrappers, reasons for rejection are by US examiners.</p> <p>102 - Non-novel subject matter 103 - Obvious subject matter DBL - (101) Double patenting, claim is anticipated or obvious in view of another claim in a separate patent filed by the same applicant</p>	CAT/CTN=103
<p>Cited patents (raw information)</p> <p>- Publication number</p> <p>- Publication country</p>	/CT	<p>Search by presence of the CT field</p> <p>Search by standardized patent number in the format CCNNNNNNNN (same as the PN field) or by the patent number in the format of the office.</p> <p>Search by two letter country code</p>	<p>CT=YES</p> <p>US20120000720 /CT US2012000720 /CT</p> <p>EP/CT</p>

Legal Status

Events

Search by	Index	Search Hints	Examples
Free text on events	/ACT	Search in English or in the application language by using single words or phrases, and truncation. <u>Note:</u> Left-hand truncation is not authorized. As ACT is structured in subfields, it allows precise searches. See hereafter for searching in subfields.	(SEARCH REPORT) /ACT ((NON PAYMENT) OR (FAILURE 1W PAY+))/ACT
<u>Data calculated by Questel:</u>			
State	STATE	Search with the keywords : - ALIVE - DEAD* Use the STATE subfield	STATE/ACT=ALIVE STATE/ACT=DEAD
Status	STATUS	Search with the keywords: - PENDING - GRANTED - EXPIRED - LAPSED* - REVOKED Use the STATUS subfield * Pending applications for which there is no activity for several years are declared "Pending Application Likely abandoned" and therefore LAPSED / DEAD.	STATUS/ACT=GRANTED STATUS/ACT=LAPSED STATUS/ACT=PENDING OR STATUS/ACT=GRANTED
Actual or expected expiration date	EED	Search with the date format: YYYY-MM-DD YYYY-MM YYYY Use the EED subfield and numeric operators: =, <, >, <=, >=.	EED/ACT=2020-15-03 EED/ACT>=2010-11 EED/ACT<=2015
STATE, STATUS and EED subfields are also provided for countries not covered by the EPO PRS database.			
Date of event publication / communication	AD	Search with the date format: YYYY-MM-DD YYYY-MM YYYY	AD/ACT=2010-06-16
Effective date of the event only available for certain events as reassignments, post-grant lapse)	EFFD	Use numeric operators: =, <, >, <=, >=.	EFFD/ACT>=2010-06 (AD/ACT>2020-11 OR EFFD/ACT>2020-11) S EG/ACT=ENP

Events (cont'd)

Search by	Index	Search Hints	Examples
Event code**	CO	Search in the format CC/NNNN. CO = Country code NNNN = 2 to 4 character alphanumeric code Use the numeric operator =. Use the P (paragraph) operator to connect the search criteria	CO/ACT=US/FP CO/ACT=EP/PGFP (CO/ACT=US/EXMR P (BARKAI D RAPHAEL)/ACT)
Index assigned to the event	SI	This index specifies if the event is positive or negative. - POS (positive) - NEG (negative) Use the numeric operator =.	SI/ACT=POS SI/ACT=NEG
Event groups 27 groups listed page 38	EG	To facilitate researching actions, Questel created event groups that bring together similar actions of different patent offices: Search with a code and the numeric operator =.	EG/ACT=ENP EG/ACT=SPC
<u>Countries affected by the event:</u> - Application country - Publication country - Designated countries	APC PC CC	Search with country code and the numeric operator =. These subfields are useful in combination with other queries to restrict the search to a particular country. Use the P (paragraph) operator to connect the search criteria.	PC/ACT=EP CC/ACT=FR (PC/ACT=FR OR CC/ACT=FR) P EG/ACT=SPC (PC/ACT=US OR CC/ACT=US) P STATUS/ACT=GRANTED
<u>Dates affected by the event:</u> - Application date - Publication date - Application date in countries designated by a WO or an EP - Date of publication in the country designated by a WO or an EP	APD PD CAPD CPD	Search with the date format : YYYY-MM-DD YYYY-MM YYYY Use numeric operators : =, <, >, <=, >=.	APD/ACT>=2005-12 PD/ACT<=1990 CAPD/ACT<=1995-05 CPD/ACT=2008-07-04 CPD/ACT=2008-01:2008-04
** The list of event codes is available on the EPO website: https://webserv.epo.org/projects/d5413/rawdatapublic.nsf/b77aac3bdab98da9c1257aae005320ec?OpenView			

Events (cont'd)

Search by	Index	Search Hints	Examples
<u>Numbers affected by the event:</u> - Publication number - Application number - Stage of publication code - Application number in countries designated by a WO or an EP - Publication number in countries designated by a WO or an EP - Stage of publication code in the country designated by a WO or an EP	PN XPN XAP KD CAP CPN CKD	Search using the Questel standardized number. Search using the Questel standardized number Searching using the 1 or 2 character code. Search using the Questel standardized number. Search using the Questel standardized number. Searching using the 1 or 2 character code. Use the P (paragraph) operator to connect the search criteria.	PN/ACT=EP0982976 XPN/ACT=EP-982976 XAP/ACT=1999EP-0971113 KD/ACT=B1 PC/ACT=EP P KD/ACT=B1 CAP/ACT=2014TH-3010056 CPN/ACT=EP1414368 CC/ACT=EP P CKD/ACT=A1
<u>US examiners' reason for rejection</u> - Reason for rejection List of Rejection types page 39 - Rejection citation number - Rejection date - Rejection status (final, non-final)	R4R RJCT RJD RJST	Search by reason rejection code Search by US publication number Search with the date format: YYYY-MM-DD YYYY-MM YYYY Search by keyword FINAL or NON-FINAL	R4R/ACT=103A RJCT/ACT=US20050145863 RJD/ACT=2015 RJD/ACT=2015-01 RJD/ACT=2015-01-13 RJST/ACT=FINAL
Supplementary Protection Certificate number	SPC	Search by presence of the field, or by the SPC number	SPC/ACT=YES SPC/ACT=N208054
Expiry date (essentially GB designated by an EP) Extension date (for some RU, EP and US)	EXD EXTD	Search with the date format: YYYY-MM-DD YYYY-MM YYYY Use numeric operators: =, <, >, <=, >=.	EXD/ACT>=2001-12-01 EXD/ACT>=2001-12 EXD/ACT>=2001 EXTD/ACT>2005

Events (cont'd)

Other subfields of the /ACT index:			
Date of maintenance fee payment (for countries designated by an EP)	PAY	Search with the date format: YYYY-MM-DD YYYY-MM YYYY	PAY/ACT=2011-02
Year number (1 to 20) of payment (US, EP)	YR	Use numeric operators: =, <, >, <=, >=.	YR/ACT=20 YR/ACT>=3
Number of extension days (US)	XDAY		XDAY/ACT>=300

Names

Search by	Index	Search Hints	Examples
Owner(s) – original and current	/OWR	The field is present when there have been changes in ownership. Addresses are not systematically included.	(QUADRANT DRUG DELIVERY) /OWR ((INT+ W BUS+ W MAC+) OR IBM) /OWR
Inventor(s)	/INV	The field is usually present when there have been changes or corrections to an inventor's name or address	(PEREIRA S ALEXANDRE) /INV
Representative (Essentially available for EP, DE, CH, NO)	/REP	The field is present when there have been changes to the representative.	(ISLER AND PEDRAZZINI) /REP
Opponent (Essentially available for EP documents)	/OPP		GEROLYMATOS /OPP
Requestor (Essentially available for AU, EP documents)	/REQ	The field is present when there are: licenses, SPC, mortgages, cancellation of financial interests..	(HSBC BANK) /REQ
All the names	/NAM	The /NAM Super Index simultaneously searches the OWR, INV, REP, OPP and REQ fields.	((INT+ W BUS+ W MAC+) OR IBM) /NAM
Search by single words (operators) or by phrases (implied adjacency). Truncation may be used.			

Other index

All countries where the patent is alive (Data calculated by Questel)	/PTCC	Search using: <ul style="list-style-type: none"> • Presence of the field • The country code with the CC subfield • The status PENDING or GRANTED with the STATUS subfield • To combine country code and status, use the P operator. 	PTCC=YES CC/PTCC=DE STATUS/PTCC=GRANTED CC/PTCC=US P STATUS/PTCC=PENDING
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Count Fields

Search by	Index	Search Hints	Examples
Numeric content at patent level	/NUM	Search for number of figures, claims, etc NUM is structured in subfields. Search using the subfield name in /NUM combined with numeric operators : =, >, <, >=, <=	NDR/NUM>=20 NFG/NUM<=50 NCL/NUM=10:15 ECL/NUM=1
See hereunder the list of subfields			
Search by	Subfield	Search by	Subfield
Art unit (US)	ART	Number of cited patents with high relevancy codes I, X or Y	NCTHI
US exemplary claim	ECL	Number of drawings (US)	NDR
Extension days (US granted)	EXTD	Number of figures (US)	NFG
Independent claim number	ICL	Number of independent claims (US)	NICL
Number of designated states	NBDS	Number of national designated states	NNDS
Number of Inventors	NBIN	Number of months between Application date and Published Application date	NPDA
Number of Assignees	NBPA	Number of months between Application date and Granted date	NPDG
Number of claims (available for authorities with English fulltext*)	NCL	Number of regional designated states	NRDS
Number of cited patents	NCT	Number of non-self cited patents	NSCT
Number of citing patents	NCTG	Number of Non self citing patents	NSCTG
Number of citing patents with high relevancy codes I, X or Y	NCTGHI	Term of expiration (years) - (US granted)	TRM
* For English full text coverage details (native English and English translation): https://static.orbit.com/imagination/orbit_welcome/prd/coverage/coverage.htm			

Other Indexes

Search by	Index	Search Hints	Examples
Litigation cases : - Involved party - Country - ID number	/CIDI	Search by: - Presence of the field - Involved party - Role Plaintiff. Combine 0PLA code and the involved party using S operator. - Role Defenfant. Combine 0DEF code and the involved party using S operator. - Country code using the CC subfield - ID number using the ID subfield • To combine country code and involved party, use the P operator. • To combine country code and involved party and role:	CIDI=YES IBM/CIDI (0PLA S (IBM))/CIDI (0DEF S (IBM))/CIDI CC/CIDI=US ID/CIDI=1817197 (((IBM)/CIDI P (CC/CIDI=US))) (("0PLA" S (IBM))/CIDI P (CC/CIDI=US))
Opposition cases: - Involved party - Country - ID number	/OPPI	Search by: - Presence of the field - Involved party - Role Plaintiff. Combine 0PLA code and the involved party using S operator. - Role Defenfant. Combine 0DEF code and the involved party using S operator. - Country code using the CC subfield - ID number using the ID subfield • To combine country code and involved party, use the P operator. • To combine country code and involved party and role:	OPPI=YES CUREVAC/OPPI (0PLA S (CUREVAC))/OPPI (0DEF S (CUREVAC))/OPPI CC/OPPI=DE ID/OPPI=1662348 (((QUALCOMM))/OPPI P (CC/OPPI=US))) (("0DEF" S (QUALCOMM))/OPPI P (CC/OPPI=US))
License ID number - US documents (KTMINE source)	/LID	This field is present for US documents which have a license agreement. Access to the license content is available with a subscription.	LID=YES 13041/LID
Notes	/NO	For U.S. documents, /NO allows to search by USPTO examiner names and company representative names. For EP and WO documents, /NO contains information on divisions, changes or corrections. Search by single words or phrases, or by presence of the field.	NO=YES (BARKAI D RAPHAEL) /NO (REQUEST 1D CORRECTION) /NO

Update Codes

Search by	Index	Search Hints	Examples
New documents in the collection: - Weekly - Monthly	/UP /UP4	<p>Use the relevant update index and search the code in the following format:</p> <p>YYYY-WW (week) YYYY-MM (month) YYYY+ (year)</p>	2014-23 /UP 2018+/UP 2014-06 /UP4
<ul style="list-style-type: none"> • Addition of publication stages: - Weekly - Monthly • Addition of citations (weekly) 	/UE /UE4 /UCT		2014-23 /UE 2014-06 /UE4 2014-23 /UCT
<ul style="list-style-type: none"> • Addition of Human produced English Abstracts 1st time: - Weekly - Monthly • Addition of Machine or Human produced English Abstract 1st time: - Weekly - Monthly • Addition of any Human language abstract 1st time: - Weekly - Monthly 	/UAB /UAB4 /UMTA /UMT4 /UABA /UAA4		2014-23 /UAB 2014-06 /UAB4 2014-23 /UMTA 2014-06 /UMT4 2014-23 /UABA 2014-06 /UAA4
Addition of CPC, IPC or US PCL codes for the 1st time	/UCL		2014-23 /UCL 2014+ /UCL
Entry of new documents in the collection + Changes to documents already in the collection: - Weekly - Monthly	/QW /QM		2014-23 /QW 2014-06 /QM 2014+ /QW
First time a publication stage receive a fulltext - Weekly - Monthly	/UPFT /UPF4	Includes: - New record entered into the collection with a fulltext - Modified record by the addition of a fulltext or by the addition of a new publication stage with a fulltext	2021-30/UPFT 2021-06/UPF4
All the update codes above are available for use in alerts.			

Update Codes (cont'd)

Search by	Index	Search Hints	Examples
Entry or update week of events (ACT)	/EUP	Use the relevant update index and search the code in the following format: YYYY-WW (week) YYYY+ (year)	2013+ /EUP 2013-47 /EUP
Entry or update week of any legal status information	/LGUP*		2012-09 /LUP 2012+ /LGUP
All the update codes above refer to legal status updates. * Only this update code is available for alerts.			

Definition of Field Codes

Biblio

AB*	Abstract in the preferred language	page	4
AP	Application data (numbers and dates)	page	9
APD	Application date	page	9
APID	Patent accession number in FullPat and FamPat collections	page	10
APL	Filing language	page	9
BPA	Parent Company Name	page	20
CIDI	Litigation cases	page	30
CPC	Cooperative Patent Classification codes – most recent publication stage	page	13
CPCG	Combination group of CPC	page	13
CPCH	Cooperative Patent Classification codes – all publication stages	page	13
CPCM	Main code of the Cooperative Patent Classification	page	13
CT	Cited patents	page	24
CTN	Standardized cited patents	page	23
CTGN	Standardized citing patents	page	23
DS	Designated countries	page	10
EAB	Original or machine translated English abstract	page	4
EC	European ECLA and ICO classification codes	page	14
EFAN	Extended family accession number	page	10
EPAP	Application date of parent EP	page	9
EPRC	Earliest priority country	page	11
ETI	Original or machine translated English title – most recent publication stage	page	3
ETIH	English title – at each publication stage	page	3
FAB	Original French abstract	page	4
FAN	PamPat Family Access Number	page	10
FD	Filing details	page	10
FI	Japanese FI classification	page	15
FID	EPO Family ID	page	10
FTI	Original French title – most recent publication stage	page	3
FTIH	French title – at each publication stage	page	3
FTM	Japanese F-term classification	page	15
GAB	Original German abstract	page	4
GTI	Original German title – most recent publication stage	page	3
GTIH	German title – at each publication stage	page	3
IC	International Patent Classification codes – most recent publication stage	page	12
ICH	International Patent Classification codes – all publication stages	page	12
ICM	Main code of the International Patent Classification	page	12
IKD	Country codes and status	page	7
IN	Inventor(s') name(s) – most recent publication stage	page	16
INAD	Inventor(s') address(es) – country and US state	page	16
INH	Inventor(s') name(s) – at each publication stage	page	16
LA	Publication language	page	8

LIC	License interest name	page	21
LID	ID number of US license	page	30
MED	Name of the drug subject to French SPC	page	3
NO	Notes in US, EP and WO documents	Page	30
NPA	Standardized name of applicant or assignee	page	18
NPR	Number of priorities	page	11
NUM	Number of drawing pages, figures, claims, etc...	page	29
OAB	Original abstract in a language other than French, English or German	page	4
OIN	Inventor name in original non-latin language	page	16
OPA	Applicant name in original non-latin language	page	17
OPD	Other publication dates	page	8
OPPI	Opposition cases	page	30
ORP	Representative name in original non-latin language	page	19
OTI	Original title in a language other than French, English or German – most recent publication stage	page	6
OTIH	Original title in a language other than French, English or German – at each publication stage	page	6
PA	Assignee name at the most recent publication stage or standardized name	page	17
PAAD	Assignee address – Country, US State, City and Post code	page	17
PAH	Applicant name at each publication stage in the EPO format	page	17
PAP	PCT filing data	page	9
PCL	US classification codes – most recent publication stage	page	15
PCLH	US classification codes – all publication stages	page	15
PCLM	Main US classification code	page	15
PD	All publication dates (except OPD)	page	8
PDA	Publication date of application	page	8
PDF	Earliest publication date	page	8
PDG	Publication date of grant	page	8
PDL	Latest publication date	page	8
PN	Publication data (numbers, status and dates)	page	7
PPN	Publication data of the original PCT application	page	7
PR	Priority data (numbers and dates)	page	11
PRD	All priority dates	page	11
PRDF	Earliest priority date	page	11
PRDL	Latest priority date	page	11
QW / QM	Week or month of entry and modification of the record	page	31
REAS	US reassignment	page	18
REF	Cited non-patent literature	page	22
RP / RPH	Representative name (for US, EP, WO and FR)	page	19
RPAD	Representative country	page	19
SEC	Security interest name (US)	page	21
STDN	Standards citing patents	page	22
STG	Definition of kind codes	page	8
TECD	Technology domain	page	12
TI*	Title in the preferred language	page	3
UAB / UAB4	Addition of Human produced English Abstracts 1st time – week & month	page	31

UABA / UAA4	Addition of any Human language abstract 1st time – week & month	page	31
UCT	Addition of citations – week	page	31
UCL	Addition of CPC or US PCL codes – week	page	31
UE & UE4	Addition of publication stage – week & month	page	31
UMTA / UMT4	Addition of Machine or Human produced English Abstract 1st time – week & month	page	31
UP / UP4	Entry of new records in the collection – week & month	page	31
UPFT / UPF4	Entry and addition of a 1 st fulltext at the publication level – week & month	page	31
XAP	Standardized application numbers	page	9
XCT	Standardized cited numbers	page	23
XPN	Standardized publication numbers	page	7
XPR	Standardized priority numbers	page	11

* Do not use =YES with TI or AB fields.

Key Content and Concepts

ADB	Advantages of the invention and drawbacks over prior art	page	5
ICLM	Independent claims	page	5
KEYW	Concepts	page	5
OBJ	Object of invention	page	5

Claims and Description

CLMS*	Claims in the preferred language	page	5
ECLM	English claims	page	5
FCLM	French claims	page	5
GCLM	French claims	page	5
OCLM	Claims in languages other than English, French or German	page	5
DESC	English description	page	5
DESX	Examples contained in the description of US documents	page	5
ODES	Description in languages other than English	page	5

* Do not use =YES with CLMS fields.

Legal Status

ACT	Event text	page 25
AD	Date of event publication/communication	page 25
APC	Application country affected by the event	page 26
APD	Application date affected by the event	page 26
CAP	Application number in countries designated by a WO or an EP	page 27
CAPD	Date of application in countries designated by a WO or an EP	page 26
CC	Designated country affected by the event	page 26
CKD	Stage of publication code in the country designated by a WO or an EP	page 27
CO	Event code	page 25
CPD	Date of publication in the country designated by a WO or an EP	page 26
CPN	Publication number in countries designated by a WO or an EP	page 27
EED	Actual or expected expiry date	page 25
EFFD	Actual date of the event	page 25
EG	Event group	page 26
EXD	Expiry date	page 27
EXTD	Extension date	page 27
KD	Stage of publication code (kind code)	page 27
PAY	Date of maintenance fee payment	page 28
PC	Publication country affected by the event	page 26
PD	Publication date affected by the event	page 26
PN	Publication number affected by the event	page 27
R4R	Reason for rejection	page 27
RJCT	Rejection citation number	page 27
RJD	Rejection date	page 27
RJST	Rejection status (final, non-final)	page 27
SI	Index assigned to the event (positive or negative)	page 26
SPC	Supplementary Protection Number	page 27
STATE	State (alive ou dead) of the members	page 25
STATUS	Status of the members	page 25
XAP	Standardized application number affected by the event	page 27
XDAY	Number of extension days	page 28
XPN	Standardized patent number affected by the event	page 27
YR	Year number of payment	page 28
EUP	Entry or update week of events (ACT) at the patent level	page 33
INV	Inventor(s)	page 28
LGUP	Entry or update week of events (ACT) at the patent family level	page 33
OPP	Opponent	page 28
OWR	Owner/Assignee	page 28
PTCC	All countries where the family is alive	page 28
REP	Representative in case of change	page 28
REQ	Requestor	page 28

List of Technology Domains

Below is the list of 35 technology domains which can be used with the index /TECD.

Analysis of Biological Materials
Audio-Visual Technology
Basic Communication Processes
Basic Materials Chemistry
Biotechnology
Chemical Engineering
Civil Engineering
Computer Technology
Control
Digital Communication
Electrical Machinery, Apparatus, Energy
Engines, Pumps, Turbines
Environmental Technology
Food Chemistry
Furniture, Games
Handling
IT Methods for Management
Machine Tools
Macromolecular Chemistry, Polymers
Materials, Metallurgy
Measurement
Mechanical Elements
Medical Technology
Micro-Structure and Nano-Technology
Optics
Organic Fine Chemistry
Other Consumer Goods
Other Special Machines
Pharmaceuticals
Semiconductors
Surface Technology, Coating
Telecommunications
Textile and Paper Machines
Thermal Processes and Apparatus
Transport

List of Event Groups

Below is the list of 27 event groups which can be used with the index EG/ACT

Event group	Definition
ACL	Accelerated Prosecutions
ADM	Administrative notifications
APL	Applicant appeals and petitions
CCL	Classification amendments
COR	Corrections, amendments
CPA	Continued Prosecution Application (US only)
DCS	Designated contracting states (WO and EP)
ENP	Entry into national phase, translations (AP, EA, EP, OA, WO)
EXM	Requests for examination, review procedures and review process, research reports
INT	Examiner Interview (US only)
LAVL	For patents declared available for licensing or sale
LIC	License event (licensed or candidate patents)
LICT	Licensing transaction(s)
NENP	Nonentry into national phase (WO and EP)
NIF	Not in force due to patent or application lapsed, expired, surrendered, withdrawn, abandoned, refusal, rejection, abandoned, etc.
NMC	Change of party name (applicant, assignee, inventor, opponent) or address
NOPP	No opposition filed
OA	Official Office Action (final rejection, nonfinal rejection, Quayle Action, Vacate 2nd Off. Action (US only)
OAI	Applicant (incoming) initiated action or response to an office action or office communication (US only)
OA0	Office action or office communication Outgoing (US only)
OPP	Opposition, reexaminations, requested by 3rd parties
PAY	Fee payment events
PIF	Patent in force
RAS	Reassignment, transfer of rights
RCE	Request for Continued Examination (US only)
RES	Restitution, restoration: in effect
SPC	Actions concerning complementary or supplementary certificates of protection, extension of protection period.

List of Rejection types

Below is the list of US Reasons for Rejection which can be used with the index R4R/ACT

All definitions listed below have been simplified for readability purposes, detailed descriptions can be found on the USPTO website. <https://www.uspto.gov/web/offices/pac/mpep/mpep-9015-appx-l.html#d0e302455>

Rejection code	Definition
100	Definitions/America Invents Act (AIA) provisions
101	Subject matter non-patentable
101ACL	ALICE, the invention does not amount to significantly more than an abstract idea
101MM	Myriad/MAYO, claims are held to claim a law of nature, a natural phenomenon or a product of nature
102a	The invention was known or used by others in this country
102b	The invention was patented or described in a printed publication in this or a foreign country
102c	The inventor intends to abandon the invention
102d	The invention was first patented or caused to be patented by the applicant more than 12 months before filing the application in the US
102e	The invention was already described in a filed application
102f	The applicant/inventor did not himself invent the subject matter sought to be patented
102g	Another inventor involved establishes that the invention was made by himself/herself and not abandoned
103a	The disclosed invention is too similar to prior art
103b	The disclosed invention is too similar to biotechnological prior art
103c	The claim is being rejected due to secondary reference (e.g. joint research agreement...)
112	Subject matter in the claims are indefinite or not properly disclosed in the specification
112a	Features in the claims are not disclosed in the specification or drawing
112b	Specification does not point out distinctly the claimed invention
112c	The claim form is rejected (dependent, independent...)
112d	The claim in dependent form is rejected due to reference (or lack of)
112e	The claim in multiple dependent form is rejected due to reference (or lack of)
112f	The element in claim for combination is rejected
121	Two or more independent and distinct inventions are claimed in one application